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# Reliability Growth

Ying Shi /Feb.18

***849 - Dependable Embedded System***

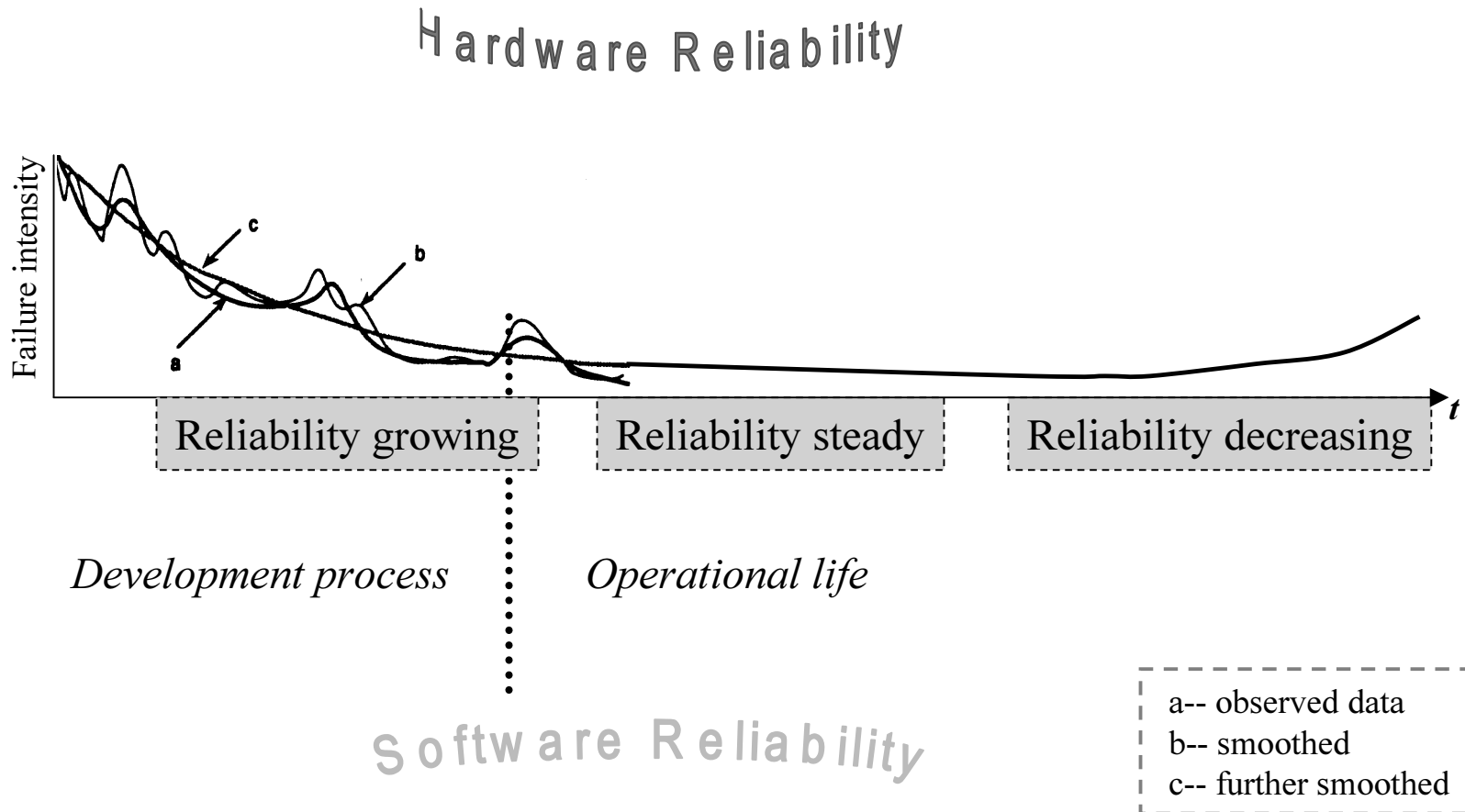
***Phil Koopman***

# Outline

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- **Overview of system life cycle**
- **What's RG**
- **What's RG Model and more about it**
- **Attention with RG application**
- **Conclusion and Future Work**
- **References**

# System life cycle



# RG Concept

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- **Not a definition:**
  - **RG is a concept that is being used as the basis for planning equipment reliability tests, assessing reliability improvement for changing equipment configurations (ref.2)**
  - **TAAF (test,analyze, and fix) almost an synonym of RG**

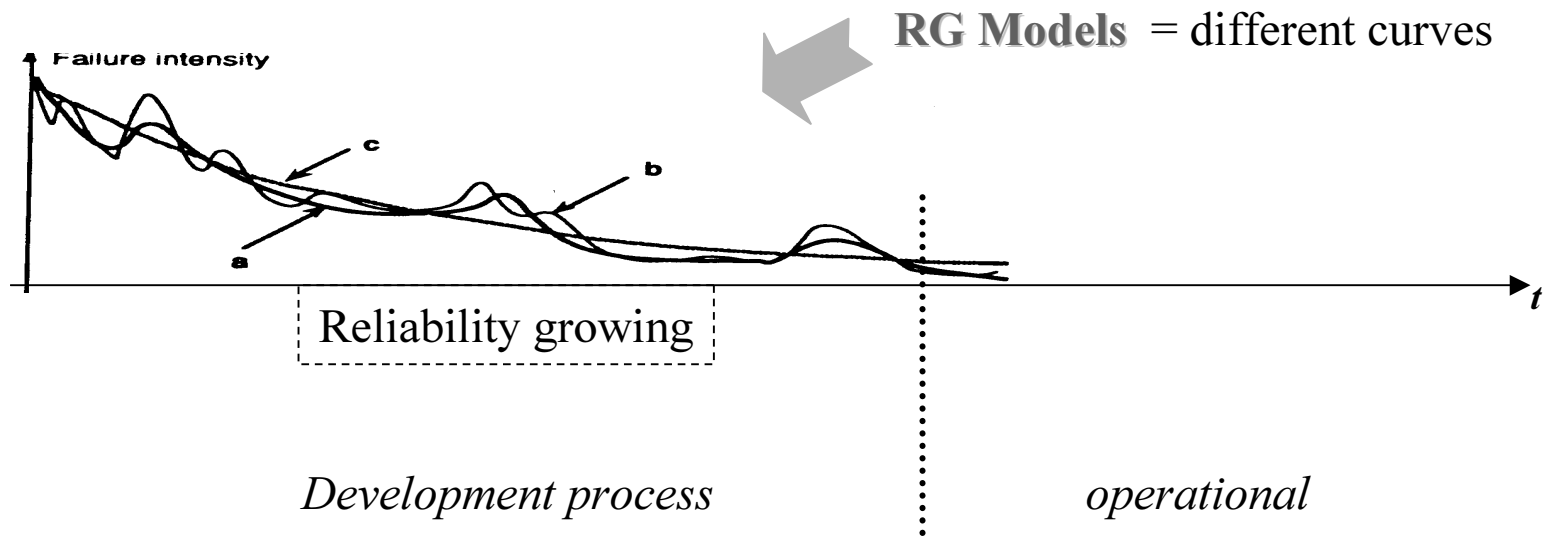
- **Definitions: (“jargon”, Meth)**

- “An improvement in reliability over time due to changes in the product design or manufacturing process is called RG” Principles of successful Reliability Growth applications, L.Crow, P.Franklin, and N.Robbins 1994 R&M
- “the positive improvement of the reliability of equipment through the implementation and permanent removal of failure mechanism”, Reliability Growth Testing , feb.3.1978
- “the positive improvement in a reliability parameter over a period of time due to changes in product design or the manufacturing process”, Reliability Growth Management, feb,13,1981
- “The improvement in reliability that results from correction of faults” IEEE standard glossary of SE terminology. 1991
- “ the system’s ability to deliver correct service is improved(stochastic increase of the successive times to failure)” J.C.Larprrie Dependability:Basic concepts and Terminology,1992

# RG Model

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Hardware Reliability



Software Reliability

# RG Model (cont.)

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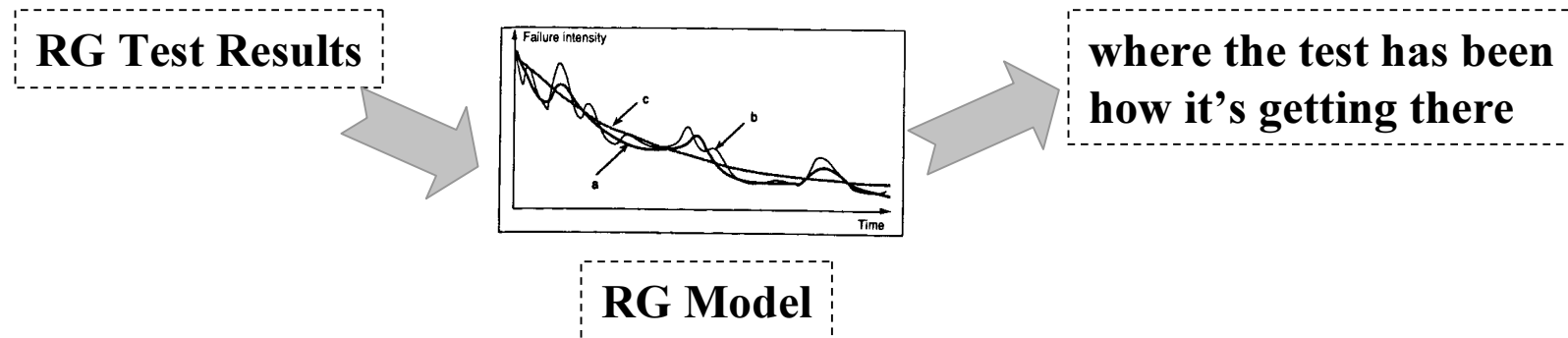
- **Why**
  - **reduce cost + time, both v.s. traditional reliability demonstration tests**
- **How**
  - **a growth model utilizes and explains growth test results; and gives an early reliability indication of where the test is headed and how it's getting there (Meth)**
- **Categories of RGM**
  - **deterministic v.s. probabilistic \***
  - **continuous v.s. discrete \***

\* *Robustness of Reliability-Growth Analysis Techniques, 92 annual R&M symposium*

\* *A Survey of Discrete Reliability-Growth Models, IEEE Trans.on Reliability, Vol,45,NO.4,96*

# Apply RG Model

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## Issues::

- **RG Test - Coverage** *Experimental-Design Techniques in Reliability-Growth Assessment, 1992 proceedings annual reliability and maintainability symposium*
- **RG Sensitivity Assessment - Parameter Selection** *Robustness of Reliability-Growth Analysis Technique, Ellis, 1992 proceedings annual reliability and maintainability symposium*

# A Critic View *(Meth)/ Extra Attention*

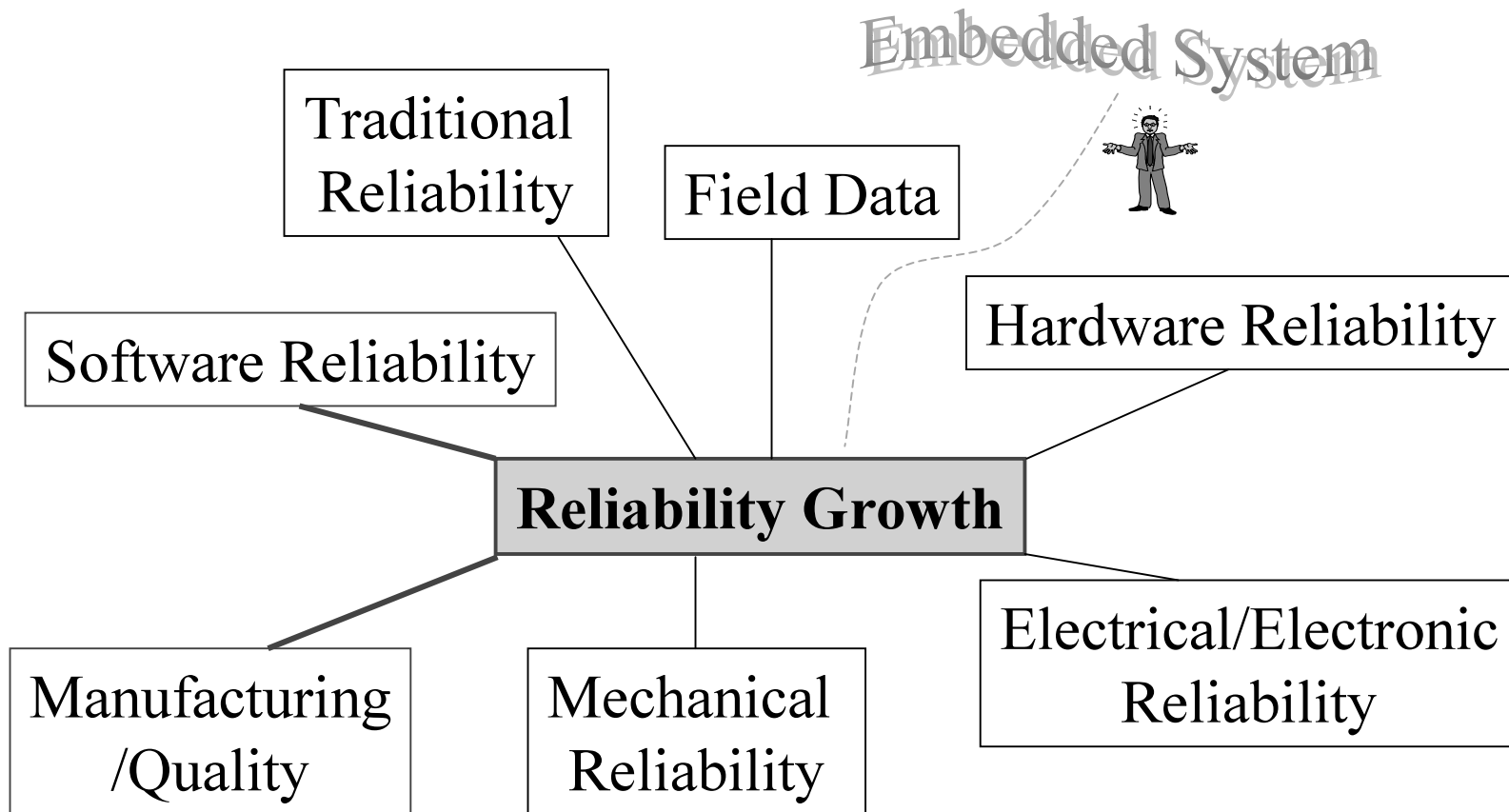
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- **Conditions where *reliability learning curve* concept seems to fit**
  - models a single reliability development test activity
  - requires failure analysis and corrective actions as part of test activity
  - applies to equipment that operates continuously
- ***Reliability learning curve* applications**
  - reasonable ::
    - determine approximate reliability test time requirements
    - monitor rate of reliability improvement in test
  - *unreasonable* ::
    - predicting equipment reliability, either current or future
    - used to combine different types of reliability test



# Connections widely

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# Conclusion and Future Work

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- **Current State**

- Work towards Operational stage almost infeasible, which means RG is almost the only place to work on in order to improve system reliability

- **Attention**

So many RGM tools, really beneficial, BUT not only better choose as simpler one as possible

- Always *avoid* applying RGM *out* of proper range
- Always stay *critical* how much can one or a combination of parameters measured can really tell you about system reliability, or how accurate

- **Future work**

- simple, robust, sensitive RGM
- High coverage test generation tool

# Reference

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- **Reliability-Growth Myths and Methodologies: A critical View, M.Meth**, *1992 Proceedings Annual Reliability and Maintainability Symposium*
- **Learning curve Approach to Reliability Monitoring, J.T.Duane**, *IEEE Trans.on Aerospace, vol.2, April 1964*
- **Paper: Achieving Reliability Growth on Real-Time System, C.Lane and J.Morrison**, *1994 proceedings Annual Reliability and Maintainability Symposium*
- **Conferences/Journals:**
  - Reliability and Maintainability Symposium
  - IEEE on Reliability
  - Software Reliability Engineering Symposium
- **Books:** *hmm... sorry ... ('\_\*)*